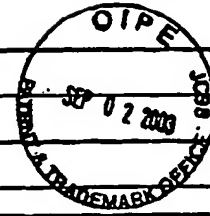


## INFORMATION DISCLOSURE CITATION

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Applicants	Shunko MAGOSHI et al.		
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## U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
<i>De</i>	5,278,421	01/11/1994	Yoda et al.	250	492.22	
<i>ke</i>	6,243,487 B1	06/05/2001	Nakajima	382	144	

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	Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>De</i>	Fumio MURAI et al., "Fast proximity effect correction method using a pattern area density map", J. Vac. Sci. Technol. B 10(6), Nov/Dec 1992, pp. 3072-3076

Examiner	<i>ZIA R. HASHHI</i>	Date Considered	<i>4/7/04</i>
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